



## P -CHANNEL ENHANCEMENT MODE POWER MOSFET

TF110P04N

## • General Description

The TF110P04M combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ .

## • Features

Advance high cell density Trench technology

Low  $R_{DS(ON)}$  to minimize conductive loss

Low Gate Charge for fast switching

Low Thermal resistance

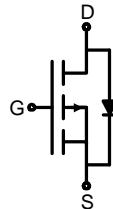
## • Application

Load Switches

DC/DC

BLDC Motor driver

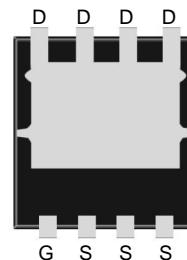
## • Product Summary



$V_{DS} = -40V$     $I_D = -50A$

$R_{DS(on)(-10V\ typ)} = 11.0m\Omega$

$R_{DS(on)(-4.5V\ typ)} = 14.0m\Omega$



PDFNWB5x6-8L

## • Ordering Information:

Part NO.	TF110P04N
Marking1	110P04N
Marking2	TF:tuofeng; Y:year code; XX:Week; AA:device code;
Basic ordering unit (pcs)	5000

• Absolute Maximum Ratings (  $T_c = 25^\circ C$  )

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	-40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D@T_C=25^\circ C$	-50	A
	$I_D@T_C=75^\circ C$	-35	A
	$I_D@T_C=100^\circ C$	-30	A
Pulsed Drain Current <sup>①</sup>	$I_{DM}$	-150	A
Total Power Dissipation <sup>②</sup>	$P_D@T_A=25^\circ C$	45	W
Total Power Dissipation	$P_D@T_A=25^\circ C$	2.0	W
Operating Junction Temperature	$T_J$	-55 to 150	$^\circ C$
Storage Temperature	$T_{STG}$	-55 to 150	$^\circ C$
Single Pulse Avalanche Energy@L=0.1mH	$E_{AS}$	155	mJ



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### •Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case <sup>②</sup>	R <sub>thJC</sub>	-	-	6.1	°C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	65	°C/W
Soldering temperature, wave soldering for 8s	T <sub>sold</sub>	-	-	265	°C

### •Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA	- 40			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	-1.2	-1.6	-2.5	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =-40V, V <sub>GS</sub> =0V			-1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A		11.0	14.0	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-15A		14.0	18.0	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =-10V, I <sub>D</sub> =-5A		12		s
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> =-15A		0.85		V

### •Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =-20V f = 1MHz	-	3210	-	pF
Output capacitance	C <sub>oss</sub>		-	238	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	226	-	

### •Gate Charge characteristics(T<sub>a</sub> = 25°C)

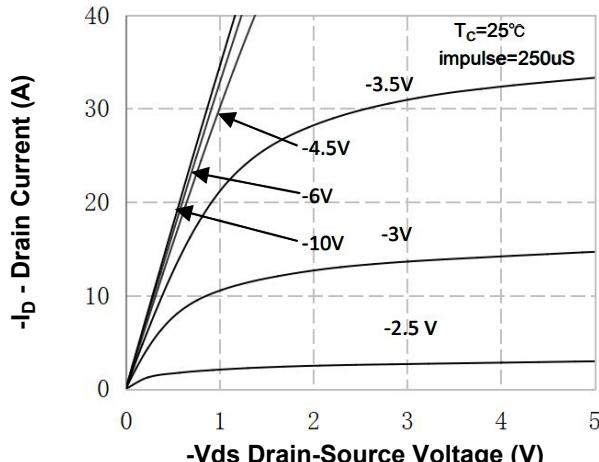
Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> =-20V I <sub>D</sub> = -20A V <sub>GS</sub> = -10V	-	42	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	7.0	-	
Gate - Drain charge	Q <sub>gd</sub>		-	8.2	-	

Note: ① Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% ;

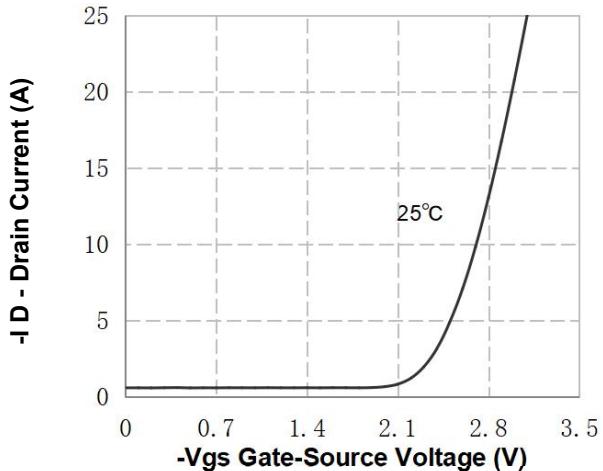
② Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;

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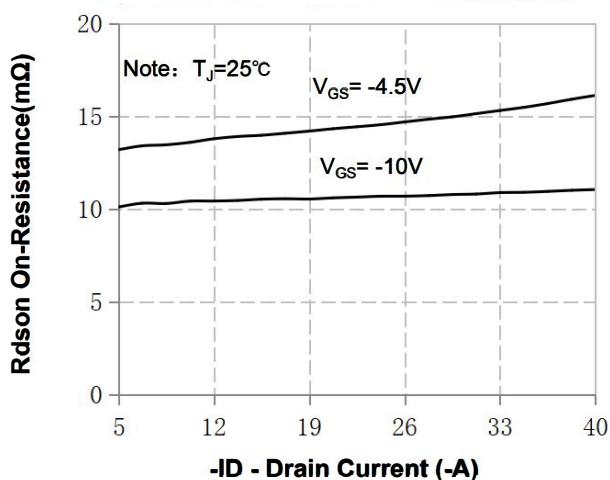
**TF110P04N**



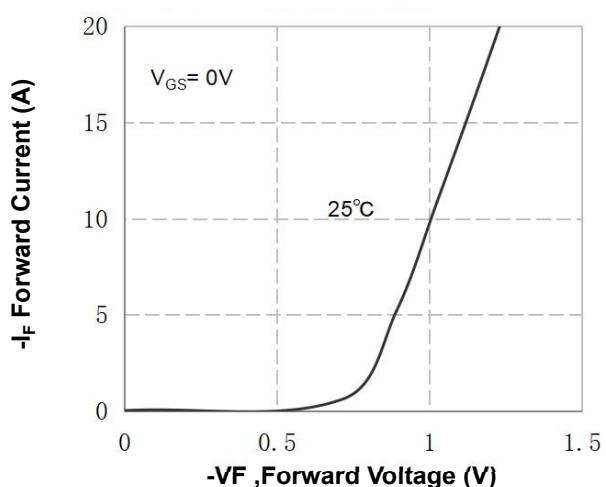
**Figure 1. On-Region Characteristics**



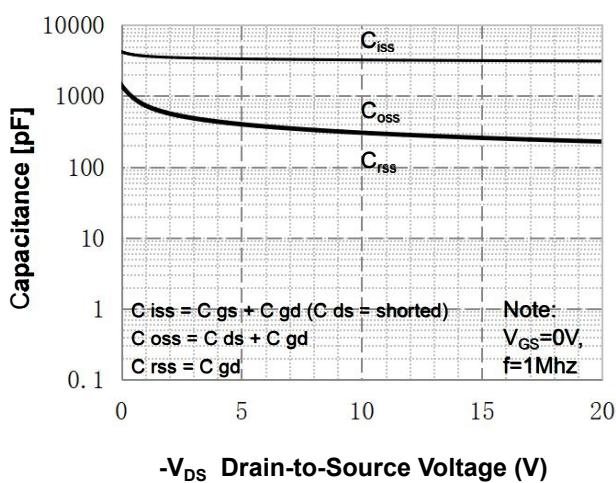
**Figure 2. Transfer Characteristics**



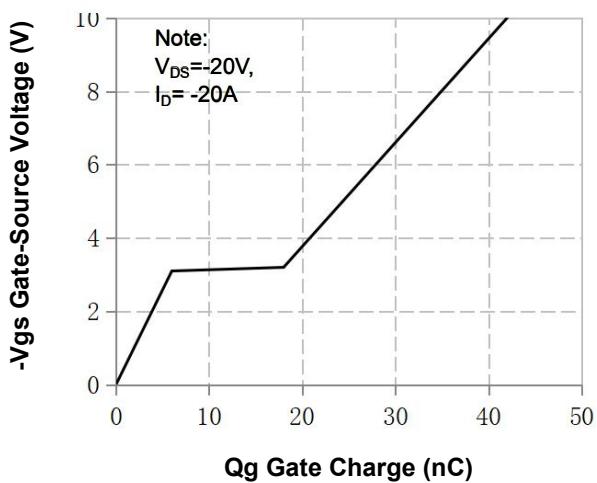
**Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**

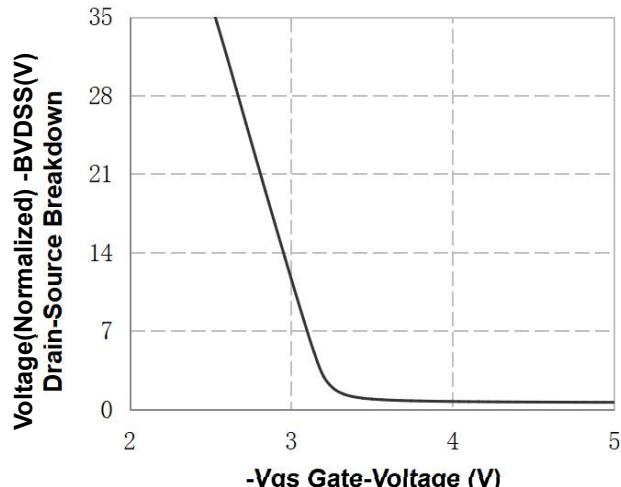


**Figure 5. Capacitance Characteristics**

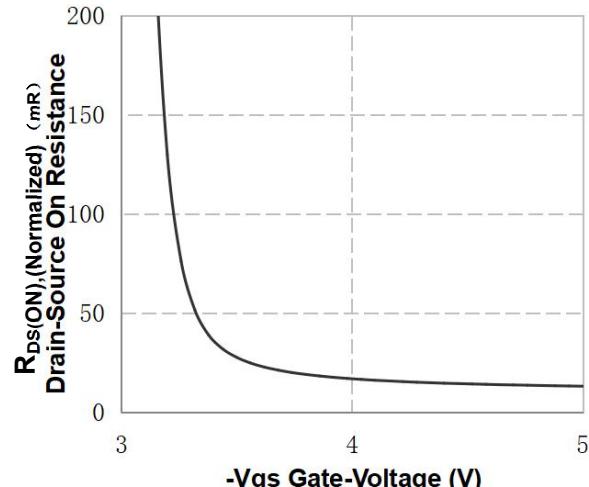


**Figure 6. Gate Charge Characteristics**

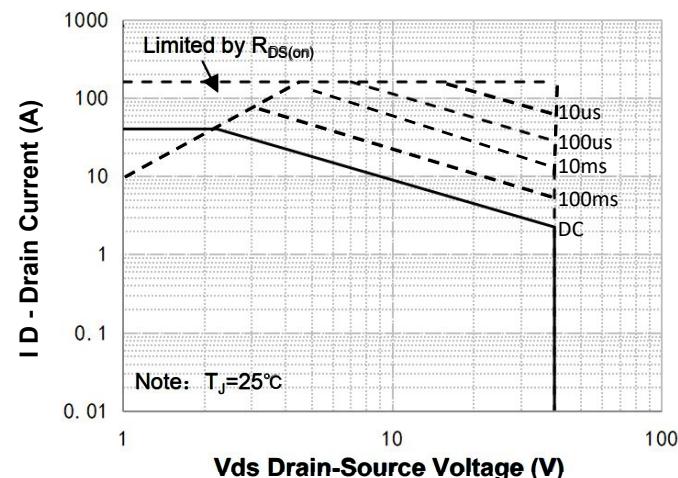
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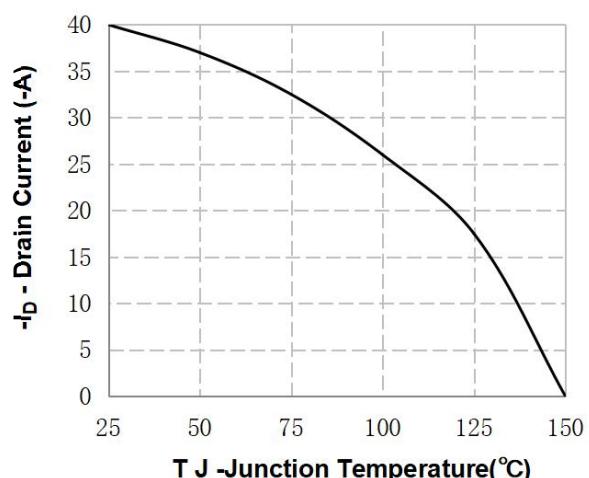
**Figure 7. Breakdown Voltage Variation vs Gate-Voltage**



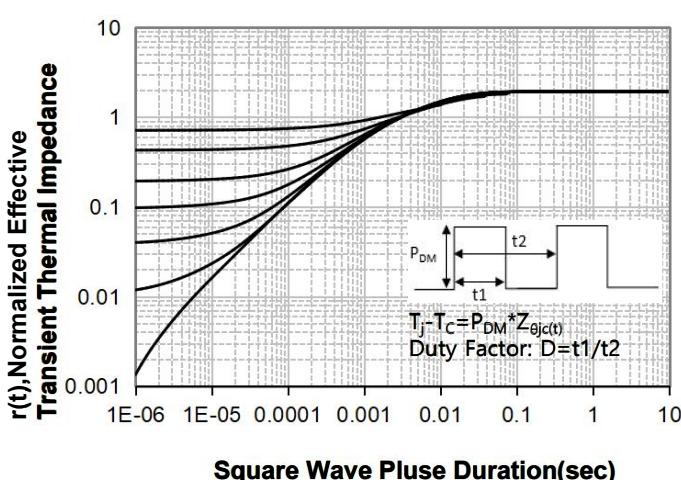
**Figure 8. On-Resistance Variation vs Gate Voltage**



**Figure 9. Maximum Safe Operating Area**



**Figure 10. Maximum Continuous Drain Current vs Case Temperature**



**Figure 11. Transient Thermal Response Curve**

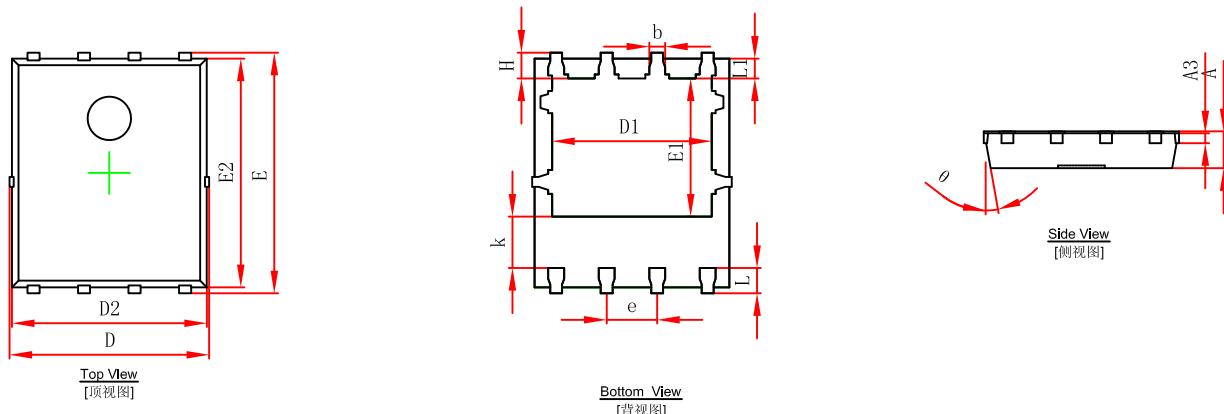


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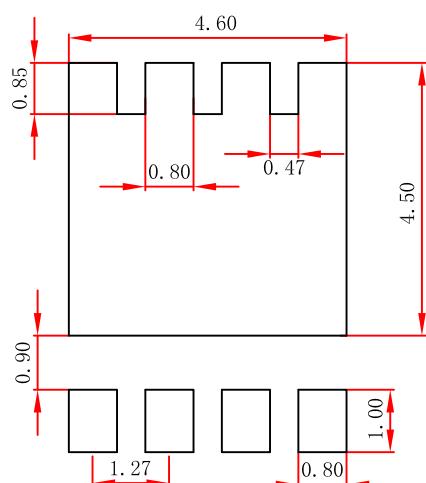
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**PDFNWB5x6-8L Package Outline Dimensions**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

**PDFNWB5x6-8L Suggested Pad Layout**



**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.05\text{mm}$ .
3. The pad layout is for reference purposes only.